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Application/Control No.	Applicant(s)/Patent under Reexamination	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE	11/22/2006	PL		
updated inventor name search PALM/EAST	11/22/2006	PL		